

DATASHEET

UF3N090350Z

900V-330mΩ SiC Normally-on JFET

Rev. B, January 2020

Description

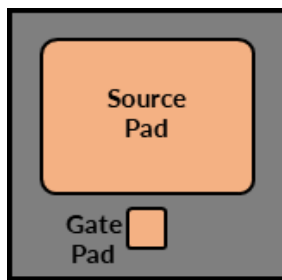
UnitedSiC offers the high-performance G3 SiC normally-on JFET transistors. This series exhibits ultra-low on resistance ($R_{DS(ON)}$) and gate charge (Q_G) allowing for low conduction and switching loss. The device normally-on characteristics with low $R_{DS(ON)}$ at $V_{GS} = 0V$ is also ideal for current protection circuits without the need for active control, as well as for cascode operation.

Features

- ◆ Typical on-resistance $R_{DS(on),typ}$ of 330mΩ
- ◆ Voltage controlled
- ◆ Maximum operating temperature of 175°C
- ◆ Extremely fast switching not dependent on temperature
- ◆ Low gate charge
- ◆ Low intrinsic capacitance
- ◆ RoHS compliant

Typical applications

- ◆ Over Current Protection Circuits
- ◆ DC-AC Inverters
- ◆ Switch mode power supplies
- ◆ Power factor correction modules
- ◆ Motor drives
- ◆ Induction heating



Part Number	Package
UF3N090350Z	Die on tape
UF3N090350	Undiced wafer



Maximum Ratings

Parameter	Symbol	Test Conditions	Value	Units
Drain-source voltage	V_{DS}		900	V
Gate-source voltage	V_{GS}	DC	-20 to +3	V
		AC ¹	-20 to +20	V
Continuous drain current ^{2,3}	I_D	$T_C = 25^\circ\text{C}$	8.4	A
		$T_C = 100^\circ\text{C}$	6.7	A
Pulsed drain current ^{3,4}	I_{DM}	$T_C = 25^\circ\text{C}$	15	A
Maximum junction temperature ⁵	$T_{J,max}$		175	$^\circ\text{C}$
Operating and storage temperature	T_J, T_{STG}		-55 to 175	$^\circ\text{C}$

1. +20V AC rating applies for turn-on pulses <200ns applied with external $R_G > 1\Omega$.

2. Limited by $T_{J,max}$

3. Assumes a maximum junction-to-case thermal resistance of $1.8^\circ\text{C}/\text{W}$

4. Pulse width t_p limited by $T_{J,max}$

5. Package limited

Electrical Characteristics ($T_J = +25^\circ\text{C}$ unless otherwise specified)

Typical Performance - Static

Parameter	Symbol	Test Conditions	Value			Units
			Min	Typ	Max	
Drain-source breakdown voltage	BV_{DS}	$V_{GS} = -20\text{V}, I_D = 1\text{mA}$	900			V
Total drain leakage current	I_{DSS}	$V_{DS} = 900\text{V}, V_{GS} = -20\text{V}, T_J = 25^\circ\text{C}$		0.8	5	μA
		$V_{DS} = 900\text{V}, V_{GS} = -20\text{V}, T_J = 175^\circ\text{C}$		4		
Total gate leakage current	I_{GSS}	$V_{GS} = -20\text{V}, T_J = 25^\circ\text{C}$		0.1	1	μA
		$V_{GS} = -20\text{V}, T_J = 175^\circ\text{C}$		0.5		μA
Drain-source on-resistance	$R_{DS(on)}$	$V_{GS} = 2\text{V}, I_D = 2\text{A}, T_J = 25^\circ\text{C}$		265		m Ω
		$V_{GS} = 0\text{V}, I_D = 2\text{A}, T_J = 25^\circ\text{C}$		330	425	
		$V_{GS} = 2\text{V}, I_D = 2\text{A}, T_J = 175^\circ\text{C}$		485		
		$V_{GS} = 0\text{V}, I_D = 2\text{A}, T_J = 175^\circ\text{C}$		575		
Gate threshold voltage	$V_{G(th)}$	$V_{DS} = 5\text{V}, I_D = 5.3\text{mA}$	-11.3	-8.8	-6.7	V
Gate resistance	R_G	f=1MHz, open drain		5.6		Ω

Typical Performance - Dynamic

Parameter	Symbol	Test Conditions	Value			Units
			Min	Typ	Max	
Input capacitance	C_{iss}	$V_{DS}=100V, V_{GS}=-20V$ $f=100kHz$		184		pF
Output capacitance	C_{oss}			24		
Reverse transfer capacitance	C_{rss}			21		
Effective output capacitance, energy related	$C_{oss(er)}$	$V_{DS}=0V$ to 600V, $V_{GS}=-20V$		15.5		pF
C_{oss} stored energy	E_{oss}	$V_{DS}=600V, V_{GS}=-20V$		2.8		μJ
Total gate charge	Q_G	$V_{DS}=600V, I_D=5A,$ $V_{GS} = -18V$ to 0V		20.8		nC
Gate-drain charge	Q_{GD}			11.4		
Gate-source charge	Q_{GS}			4.2		
Turn-on delay time	$t_{d(on)}$	$V_{DS}=600V, I_D=5A,$ Gate Driver = -18V to 0V, $R_G=1\Omega,$ Inductive Load, FWD: UJ3D1202TS $T_J=25^\circ C$		5		ns
Rise time	t_r			17		
Turn-off delay time	$t_{d(off)}$			7		
Fall time	t_f			8		
Turn-on energy	E_{ON}			43		
Turn-off energy	E_{OFF}	$V_{DS}=600V, I_D=5A,$ Gate Driver = -18V to 0V, $R_G=1\Omega,$ Inductive Load, FWD: UJ3D1202TS $T_J=150^\circ C$		8.2		μJ
Total switching energy	E_{TOTAL}			51.2		
Turn-on delay time	$t_{d(on)}$			5		
Rise time	t_r			12		
Turn-off delay time	$t_{d(off)}$			7		
Fall time	t_f			7		
Turn-on energy	E_{ON}			35.2		
Turn-off energy	E_{OFF}		6.4			
Total switching energy	E_{TOTAL}		41.6		μJ	

Typical Performance Diagrams

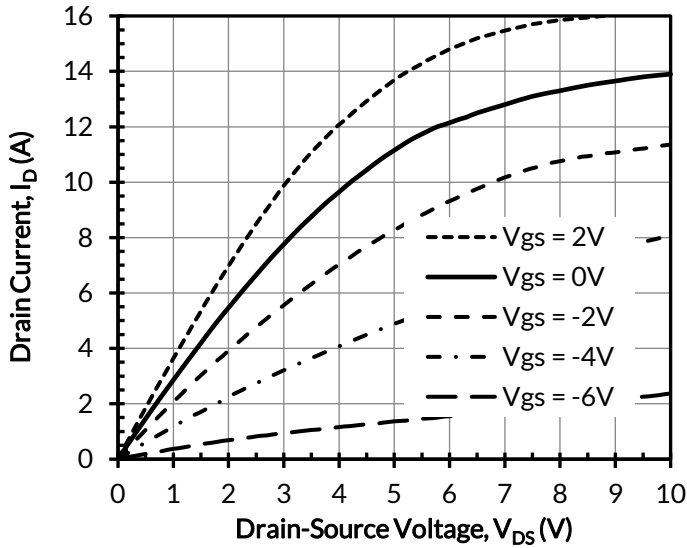


Figure 1. Typical output characteristics at $T_j = -55^\circ\text{C}$, $t_p < 250\mu\text{s}$

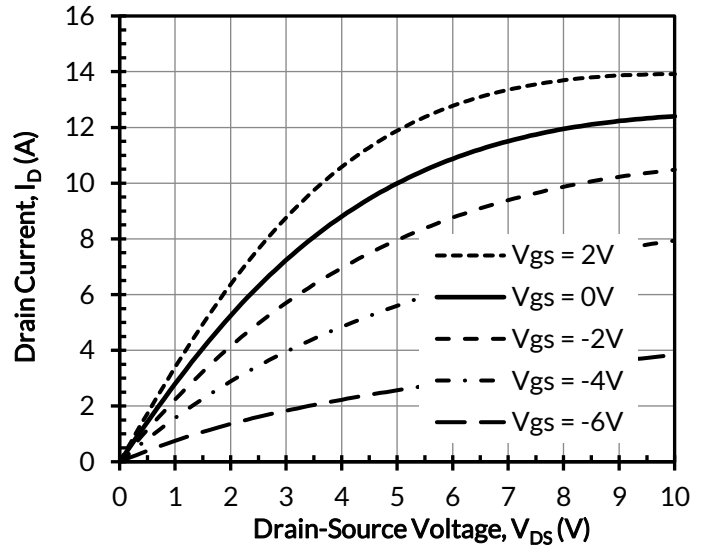


Figure 2. Typical output characteristics at $T_j = 25^\circ\text{C}$, $t_p < 250\mu\text{s}$

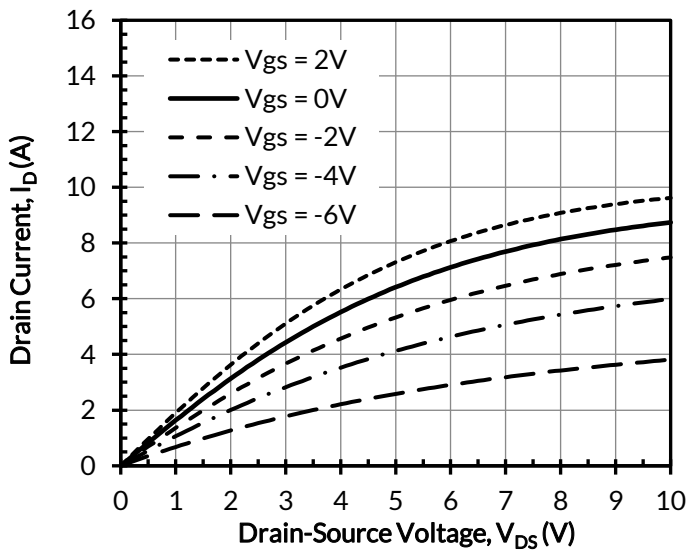


Figure 3. Typical output characteristics at $T_j = 175^\circ\text{C}$, $t_p < 250\mu\text{s}$

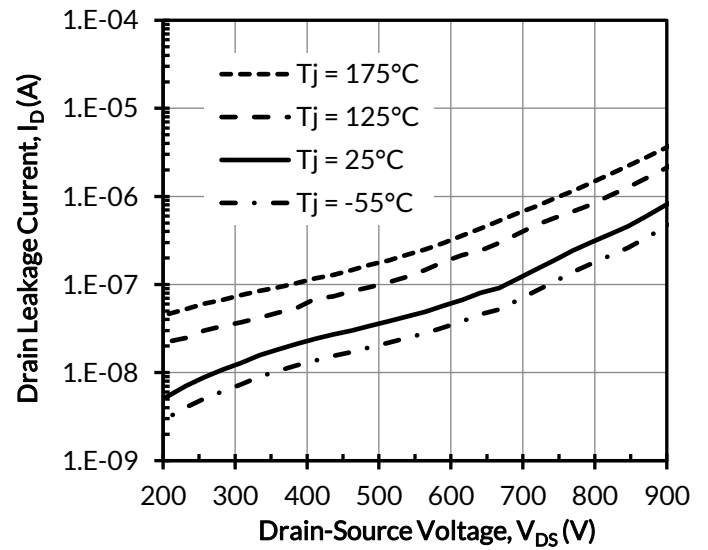


Figure 4. Typical drain-source leakage at $V_{GS} = -20\text{V}$

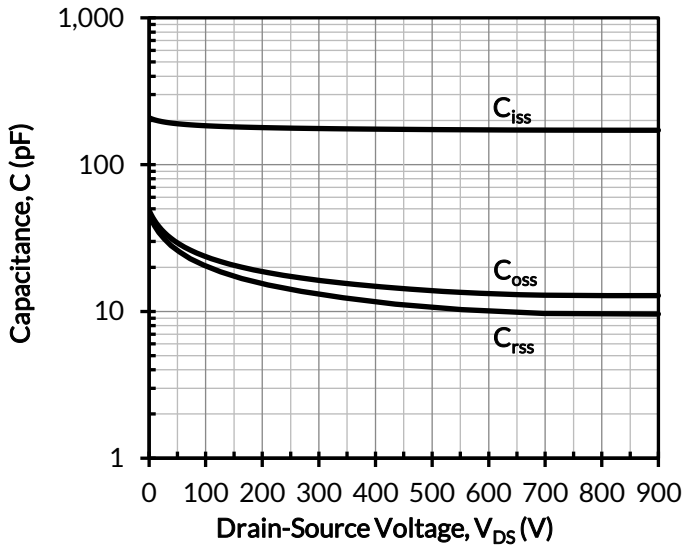


Figure 5. Typical capacitances at $f = 100\text{kHz}$ and $V_{GS} = -20\text{V}$

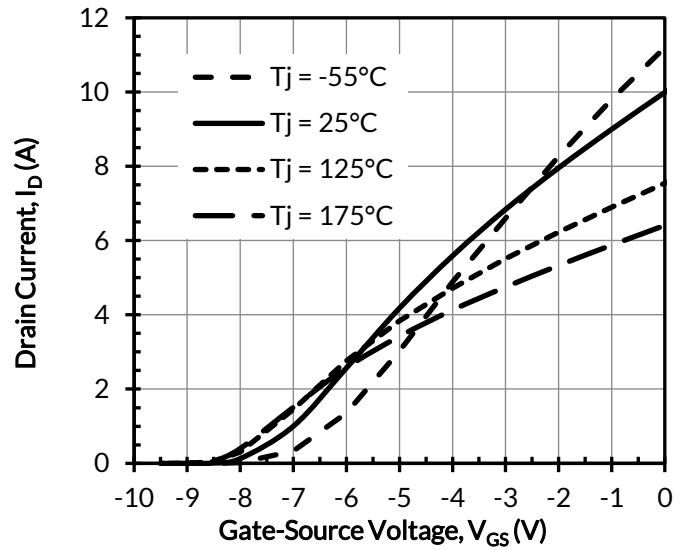


Figure 6. Typical transfer characteristics at $V_{DS} = 5\text{V}$

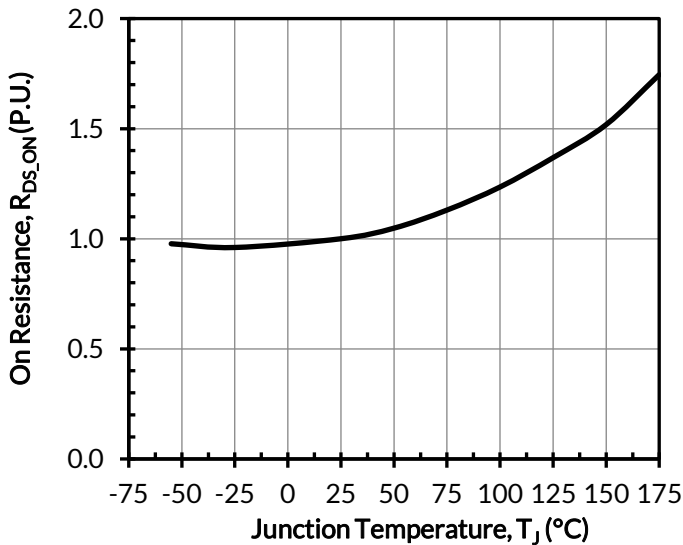


Figure 7. Normalized on-resistance vs. temperature at $V_{GS} = 0\text{V}$ and $I_D = 2\text{A}$

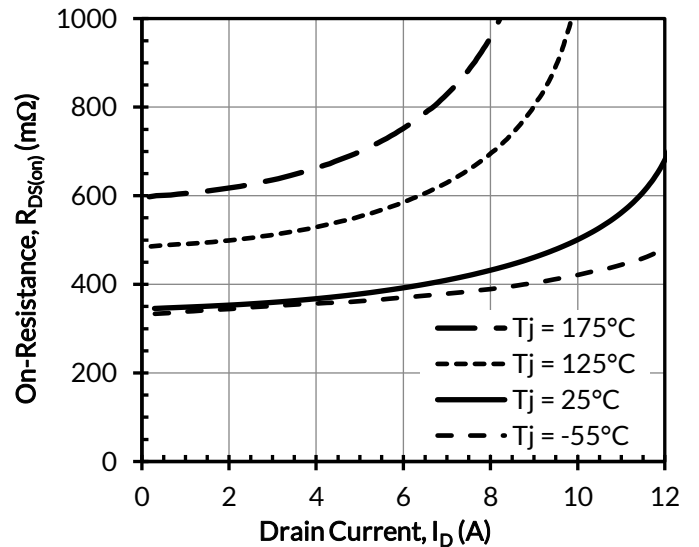


Figure 8. Typical drain-source on-resistances at $V_{GS} = 0\text{V}$

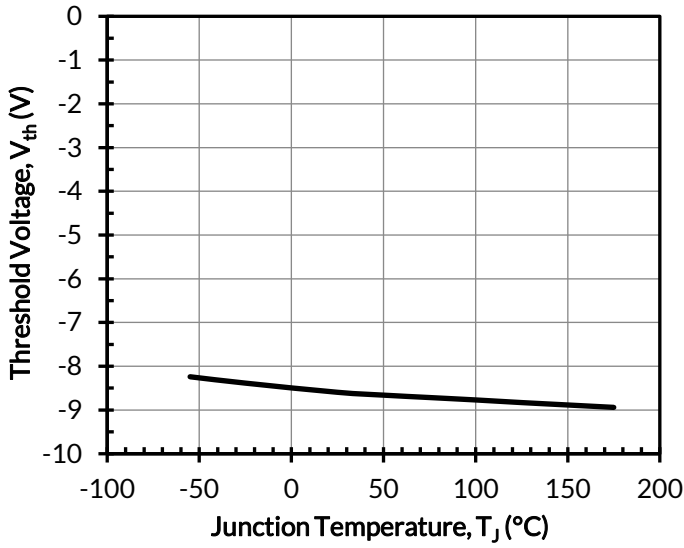


Figure 9. Threshold voltage vs. junction temperature at $V_{DS} = 5V$ and $I_D = 5.3mA$

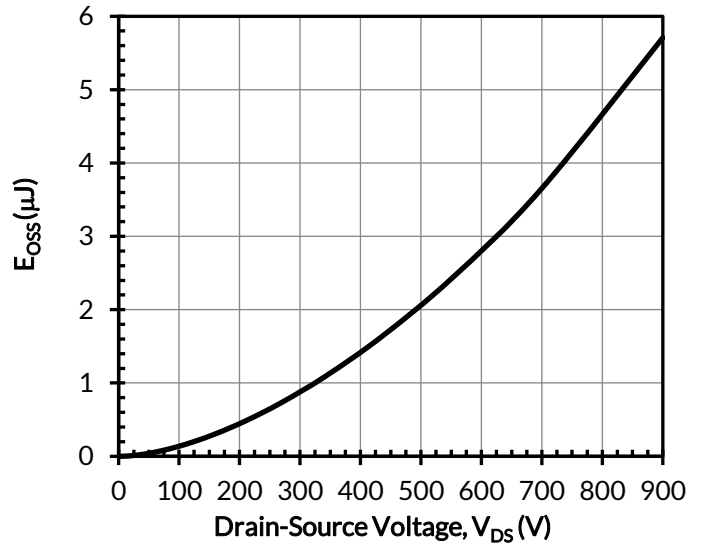


Figure 10. Typical stored energy in C_{OSS} at $V_{GS} = -20V$

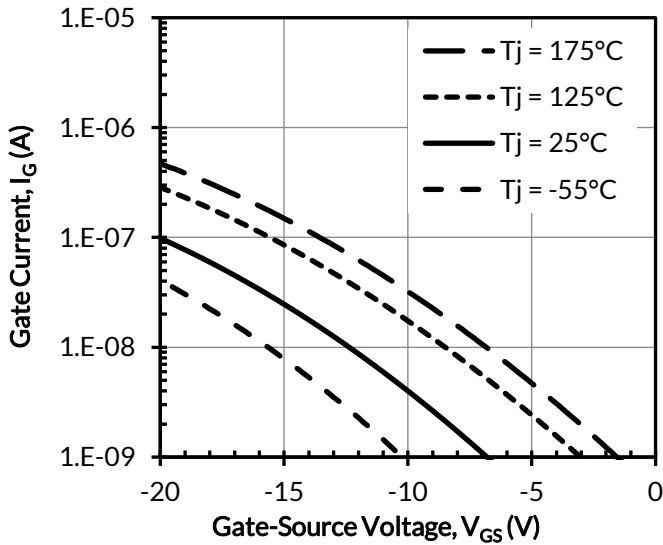


Figure 11. Typical gate leakage at $V_{DS} = 0V$

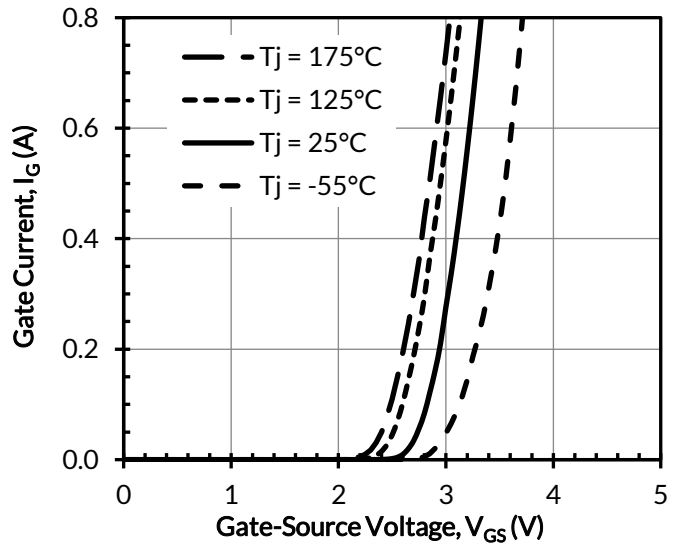


Figure 12. Typical gate forward current at $V_{DS} = 0V$

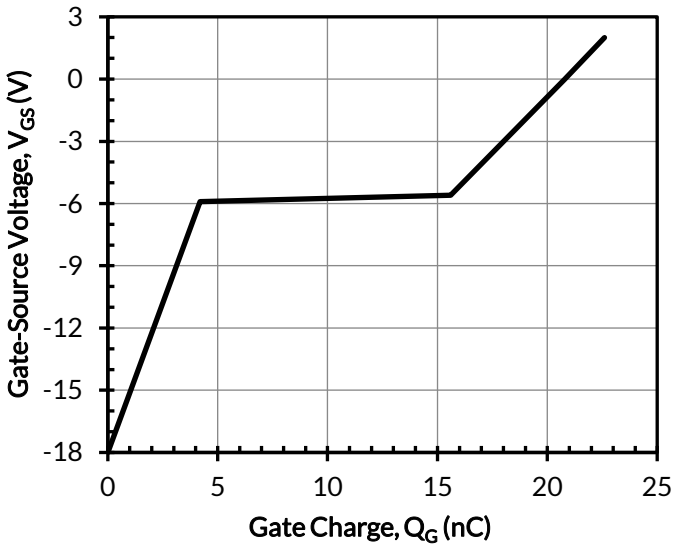


Figure 13. Typical gate charge at $V_{DS} = 600V$ and $I_D = 5A$

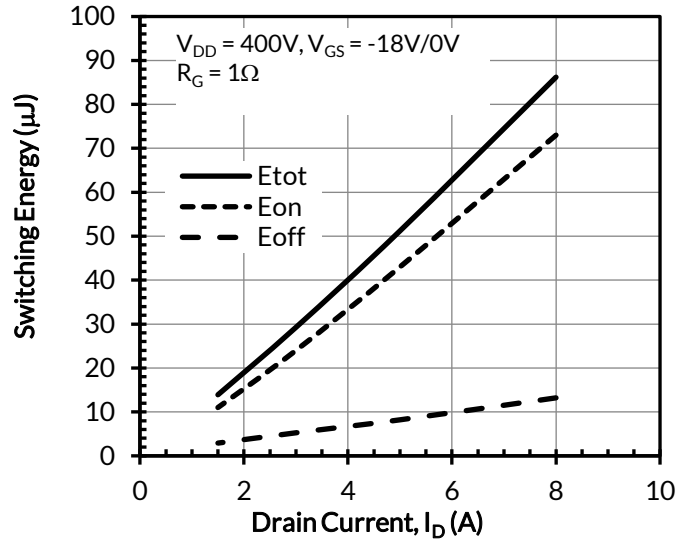


Figure 14. Clamped inductive switching energy vs. drain current at $T_J = 25^\circ C$

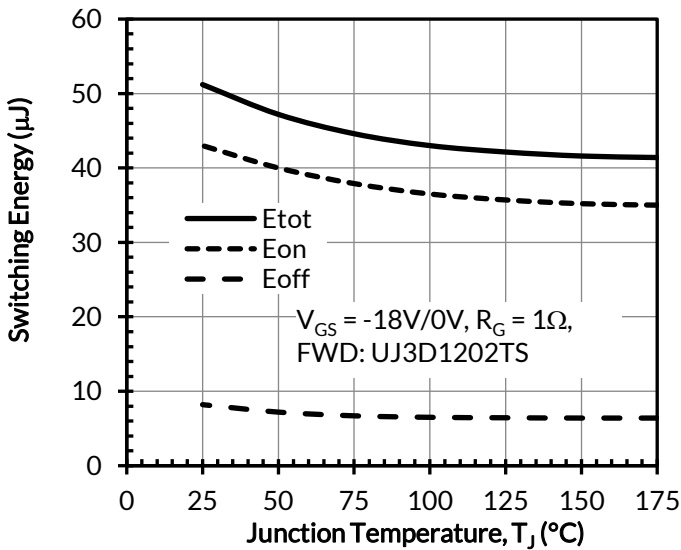


Figure 15. Clamped inductive switching energy vs. junction temperature at $V_{DS} = 600V$ and $I_D = 5A$

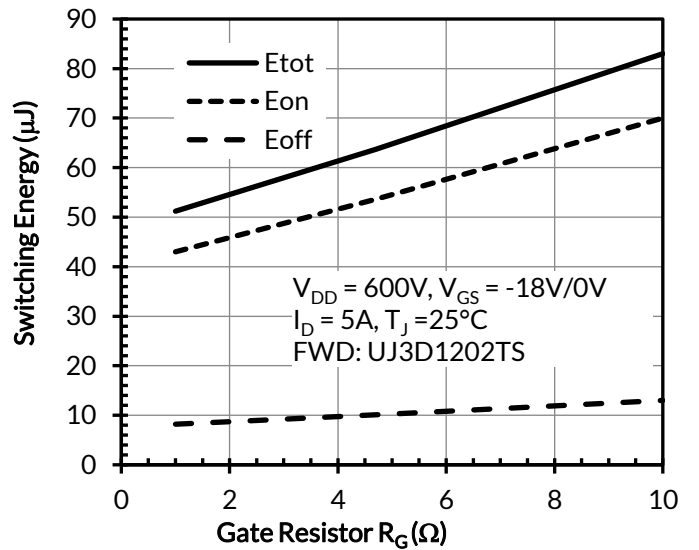
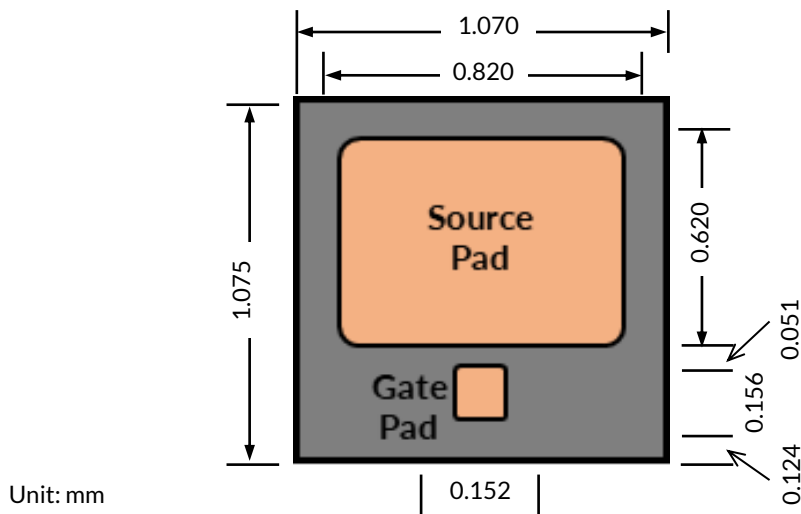


Figure 16. Clamped inductive switching energy vs. gate resistor R_G

Mechanical Characteristics

Parameter	Typical Value	Units
Die dimensions with scribe line (L x W)	1.070 x 1.075	mm
Scribe line width	80	μm
Source pad metal dimensions (L x W)	0.820 x 0.620	mm
Gate pad metal dimensions (L x W)	0.152 x 0.156	mm
Source metallization (AlCu)	5	μm
Gate metallization (AlCu)	5	μm
Backside drain metallization (Ti/Ni/Ag)	0.1/0.2/1	μm
Frontside passivation	Polyimide	
Die thickness	150	μm
Wafer size	150	mm
Gross die per wafer	12620	

Chip Dimensions



Disclaimer

UnitedSiC reserves the right to change or modify any of the products and their inherent physical and technical specifications without prior notice. UnitedSiC assumes no responsibility or liability for any errors or inaccuracies within.

UnitedSiC assumes no liability whatsoever relating to the choice, selection or use of the UnitedSiC products and services described herein.

Information on all products and contained herein is intended for description only. No license, express or implied, to any intellectual property rights is granted within this document.